

03-11-02

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Deposited: March 7, 2002

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/ Ruth Montalvo Date: 03/07/02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Customer No.

026418

Attorney's Docket No.:

JG-YY-5116/500569.20081

Applicant(s)

Masaaki TERASHIMA, et al.

U.S. Application No.:

10/006,169

Group No.:

Filed:

December 6, 2001

Examiner:

For:

DEVICE FOR MEASURING IONIC ACTIVITIES

Commissioner of Patents
Washington, D. C. 20231

INFORMATION DISCLOSURE STATEMENT

SIR:

Applicant hereby submits the following references::

	Document Number	Date	Name and/or Country
AA	4,571,293	2/18/1986	US
AB	4,789,435	12/6/1988	US
AC	4,053,381	10/11/1977	US
AD	4,171,246	10/16/1979	US
AE	4,219,968	9/2/1980	US

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Accompanying this Information Disclosure Statement and form PTO-1449 are copies of the aforementioned documents.

This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,

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Enclosures:
PTO-1449; 5 documents

LIST OF PRIOR ART CITED BY APPLICANT
 (Filed on March 7, 2002)

Docket No. JG-YY-5116/500569.20081
 Applicant(s): Masaaki TERASHIMA, et al.
 Application No. 10/006,169
 Filed: December 6, 2001

Group: --
 Examiner: --



U.S. PATENT DOCUMENTS

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
	AA	4,571,293	2/18/1986	Seshimoto et al	204	408	
	AB	4,789,435	12/6/1988	Seshimoto et al	204	1 T	
	AC	4,053,381	10/11/1977	Hambien, et al.	204	195	
	AD	4,171,246	10/16/1979	Hambien, et al.	204	1 T	
	AE	4,219,968	9/2/1980	Sakai, et al.	49	40	
	AF						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	CLASS	Sub-Class	Translation YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							
	AQ							
	AR							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AT	
AU	
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Examiner:	Date:
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.